SPECTRODENSITOME TER

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Spectrodensitometer has the capability of densitometer and measures color and numeric color differences and widely used in the ink printing

SPE75 SPECTRODENSITOMETER

45/0 geometrical optics structure, comply with CIE, the testing conditions of M O, M 1,M 2 , M 3 stipulated by ISO 13655 standard, it can accurately measure various printing density , overprint rate and other printing parameters.

Accurately measure reflectance spectrum, CMYK density and Lab value of the sample;

High-configuration electronic hardware: 3.5-inch TFT true-color screen, capacitive touch screen, concave grating, 256-pixel dual-array CMOS image sensor, etc.;

Perfect combination of the beautiful appearance and the ergonomic structure design;

Optional apertures: Φ2/4/8mm, adapt to more samples;

Large-capacity storage space, over 20,000 test data

Combined LED light sources with long life and low power consumption, including UV light;

USB/Blue2.1 dual communication mode is widely useful;

Especially suitable for process control and quality control of printing plants;

PC software has powerful function expansion.

SPECIFICATIONS

Model	SPE75-45A	SPE75-45B	SPE75-45C	SPE75-45D
Optical Geometry	45/0(45 ring-shaped illumination, 0 degree viewing angle)			
Standards compliant	ISO 5-4,CIE No.15 Compliance with ISO 13655 measurement conditions; M0 (CIE Light Soure A) M1 (CIE Light Soure D50) M2 (Excluding UV light source) M3 (M2+Polarized light filter)			
Illuminant	D65,A,C,D50,D55,D65,D75,F2(CWF),F7(DLP),F11(TL84),F12(TL83/U30),F1,F3,F4,F5,F6,F8,F9,F10(TPL5)		D65, A,C,D50,D55,D65,D75,F2,F7,F11,F12	
Spectral Mode	Concave Grating			
Sensor	256 Image Element Double Array CMOS Image Sensor			
Wavelength Pitch	10 nm			
Semi-bandwidth	10 nm			
Density Standards	ISO Status A, E, I, T			
Density index	Density value, density difference, dot area, dot enlargement, overprint, printing characteristics, printing contrast, tone error and gray scale, density scanning Customized one aperture:Φ2mm,Φ4mm,Φ8mm optional		Density value, density difference, dot area, dot enlargement, overprint, printing characteristics, printing contrast, tone error and gray level Customized one aperture:Φ2mm,Φ4mm,Φ8mm optional	
color space	CIE LAB,XYZ,Yxy,LCh,CIE LUV,HunterLAB		CIE LAB,XYZ,Yxy,Lch	
Color Difference Formula	ΔE*ab,ΔE*94,ΔE*00,ΔE*uv,ΔE*cmc(2:1),ΔE*cmc(1:1),ΔE(Hunter)		ΔE*ab,ΔE*94,ΔE*00	
Other Colorimetric data	WI(ASTM E313,CIE/ISO,AATCC,Hunter), YI(ASTM D1925,ASTM 313), MI (Metamerism Index),Opacity		/	
Observer	2° / 10°			
Measurement Time	About 1.5s			

Repeatability	Density: Within 0.01 D Chromaticity value:within ΔE*ab 0.03 (When a white calibration plate is measured 30 times at 5 second intervals after white calibration)	Density: Within 0.01 D Chromaticity value:within ΔE*ab 0.04 (When a white calibration plate is measured 30 times at 5 second intervals after white calibration)
Inter-instrument agreement	Within ΔE*ab 0.18 (Average for 12 BCRA Series II color tiles)	Within ΔE*ab 0.2 (Average for 12 BCRA Series II color tiles)
Measurement Method	Single Measurement, Average Measurement(2-99)	
Interface	USB, Bluetooth	USB